

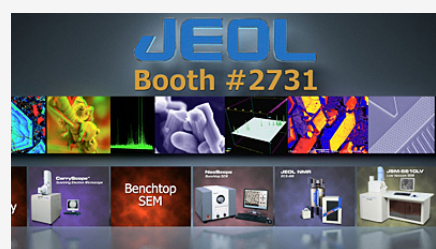
JEOL in the News

You Tube [Fayetteville State University Video of New Microprobe Installation](#)

[Museum Laboratories: Where Art Meets Science](#)

[SEM Energy Technology Advances Energy Research](#)

See Us at Pittcon 2010



JEOL Papers Presented at Pittcon

Sunday, February 28th, 2010, 2:35p.m. Room 206B
Correlative Microscopy: Concurrent SEM and Optical Imaging of Materials in Their Native State. D. Guarrera, JEOL USA, Inc.; H. Nishiyama and M. Suga, JEOL Ltd. Microscopy: New Instrumental Techniques Session

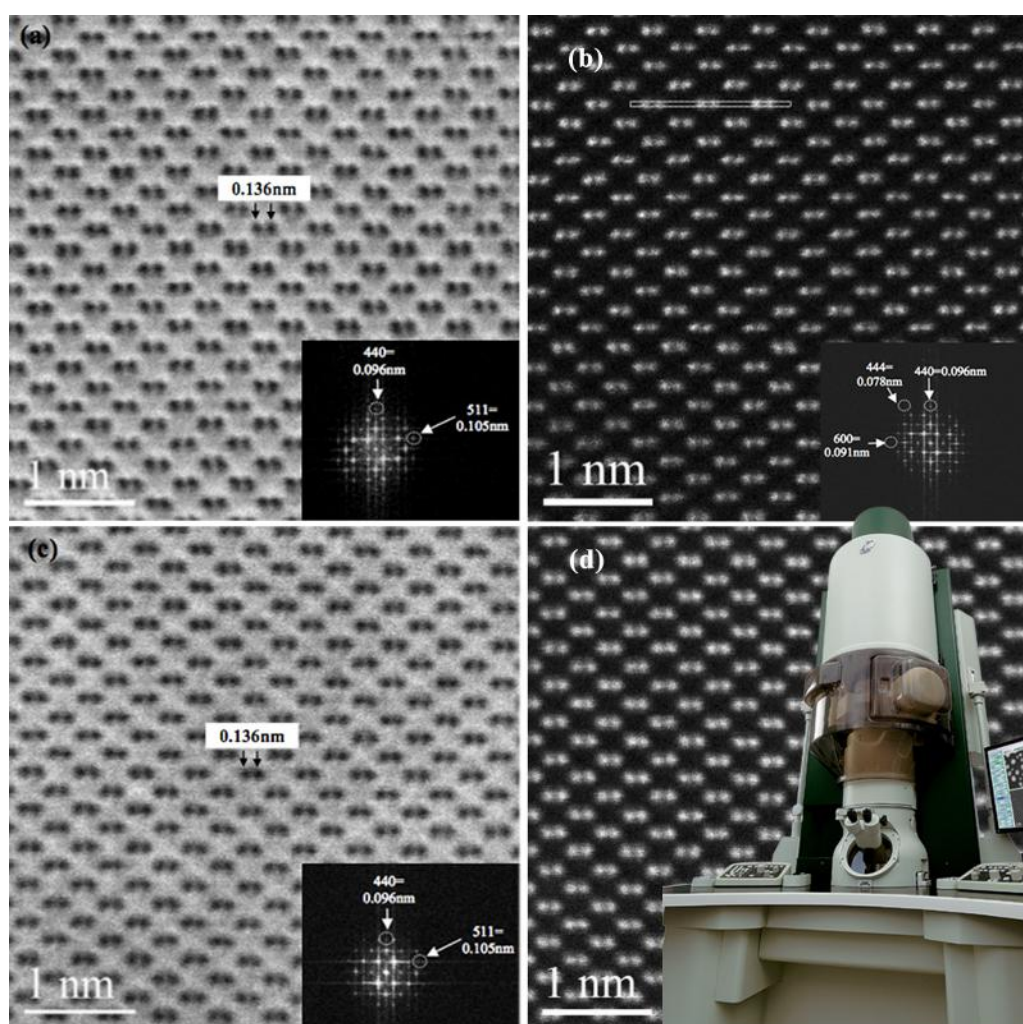
Japan Symposium
 Monday, March 1, 10:25 - 11:00 a.m. Room 207C
DART Mass Spectrometry for Security and Safety. R. Cody

JEOL Seminars 2010

Stay tuned for announcements about seminars in your area.

Electron Microscopy Nano and Beyond
 University of Texas at Dallas
 March 18, 2010
[Agenda](#)

1st JEOL ARM200F TEM Quickly Enters Picoscale Territory at UTSA



The first transmission electron microscope of its caliber to be installed, the eagerly awaited atomic resolution JEOL **JEM-ARM200F** TEM arrived at the University of Texas at San Antonio in January, and by early February began producing outstanding imaging results.

"Achieving raw HAADF images showing at least 78 picometer information transfer in just three weeks demonstrates the stability of this all-new instrument and the skill of the UTSA-JEOL team to quickly power up the first TEM of its kind," said Dr. Thomas Isabell, JEOL USA Director of the TEM Product Division.

UTSA physics and astronomy department chair [Dr. Miguel Yacaman](#), a renowned electron microscopist and nanotechnology researcher, tested the new ARM200F performance on Si <110> samples as the JEOL engineering, service and applications team worked closely together to install the TEM in [UTSA's Advanced Microscopy Lab](#).

[Read the full story and image captions >>>](#)

See JEOL at PITTCON CONFERENCE & EXPO 2010 ORLANDO · FEB 28 - MAR 5

Orange County Convention Center
Booth #2731



To schedule a demonstration on the JEOL JSM-6610LV with Thermo EDS analyzer or on the NeoScope Benchtop SEM Please contact us at jeolink@jeol.com

JEOL JSM-6610LV Scanning Electron Microscope

- ◆ Large chamber and stage
- ◆ Color navigation camera
- ◆ Ultrahigh performance backscatter detector
- ◆ Continuous bias
- ◆ Guaranteed resolution at 1kV
- ◆ High performance Thermo EDS